

DATA SHEET

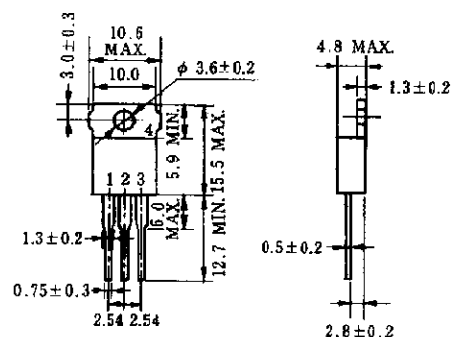
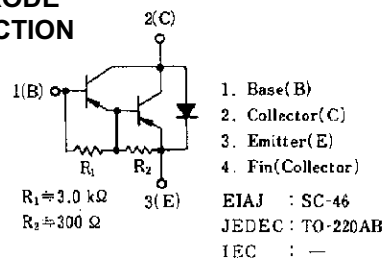
NEC**SILICON POWER TRANSISTOR
2SB601****PNP SILICON EPITAXIAL TRANSISTOR (DARLINGTON CONNECTION)
FOR LOW-FREQUENCY POWER AMPLIFIERS AND LOW-SPEED SWITCHING****FEATURES**

- High-DC current gain due to Darlington connection
- Low collector saturation voltage
- Low collector cutoff current
- Ideal for use in direct drive from IC output for magnet drivers such as treminal equipment or cash registers

ABSOLUTE MAXIMUM RATINGS ($T_a = 25^\circ\text{C}$)

Parameter	Symbol	Ratings	Unit
Collector to base voltage	V_{CBO}	-100	V
Collector to emitter voltage	V_{CEO}	-100	V
Emitter to base voltage	V_{EBO}	-7.0	V
Collector current	$I_{C(DC)}$	∓ 5.0	A
Collector current	$I_{C(pulse)}^*$	∓ 8.0	A
Base current	$I_{B(DC)}$	-0.5	A
Total power dissipation	$P_T (T_a = 25^\circ\text{C})$	1.5	W
Total power dissipation	$P_T (T_c = 25^\circ\text{C})$	30	W
Junction temperature	T_j	150	$^\circ\text{C}$
Storage temperature	T_{stg}	-55 to +150	$^\circ\text{C}$

* $PW \leq 10 \text{ ms}$, duty cycle $\leq 50\%$

PACKAGE DRAWING (UNIT: mm)**ELECTRODE CONNECTION**

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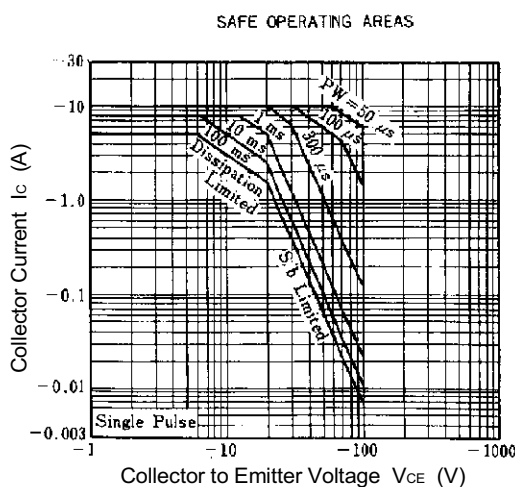
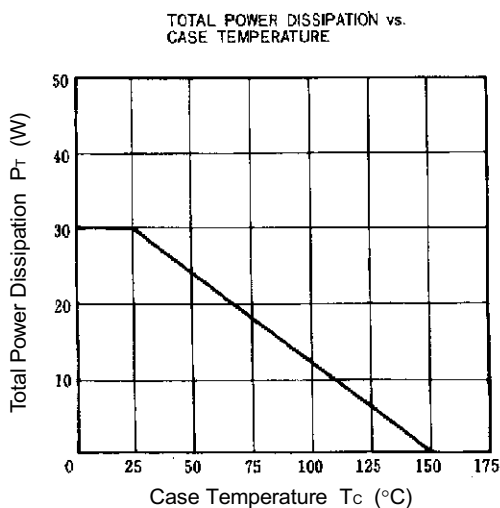
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

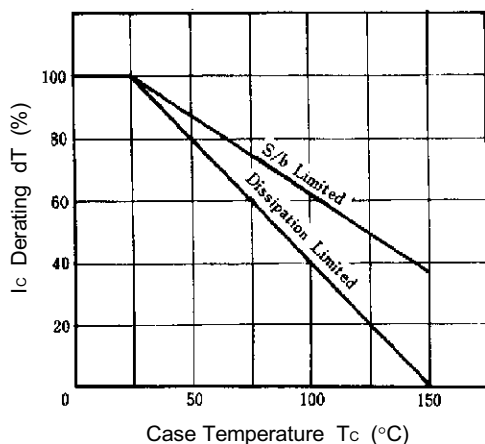
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Collector to emitter voltage	$V_{CEQ(SUS)}$	$I_C = -3\text{ A}$, $I_{B1} = -3\text{ mA}$, $L = 1\text{ mH}$	-100			V
Collector to emitter voltage	$V_{CEX(SUS)1}$	$I_C = -3\text{ A}$, $I_{B1} = -I_{B2} = -3\text{ mA}$, $V_{BE(OFF)} = 5.0\text{ V}$, $L = 180\text{ }\mu\text{H}$, clamped	-100			V
Collector to emitter voltage	$V_{CEX(SUS)2}$	$I_C = -6\text{ A}$, $I_{B1} = -12\text{ mA}$, $I_{B2} = 3\text{ mA}$, $V_{BE(OFF)} = 5.0\text{ V}$, $L = 180\text{ }\mu\text{H}$, clamped	-100			V
Collector cutoff current	I_{CBO}	$V_{CB} = -100\text{ V}$, $I_E = 0$			-10	μA
Collector cutoff current	I_{CER}	$V_{CE} = -100\text{ V}$, $R_{BE} = 51\text{ }\Omega$, $T_a = 125^\circ\text{C}$			-1.0	mA
Collector cutoff current	I_{CEX1}	$V_{CE} = -100\text{ V}$, $V_{BE(OFF)} = 1.5\text{ V}$			-10	μA
Collector cutoff current	I_{CEX2}	$V_{CE} = -100\text{ V}$, $V_{BE(OFF)} = 1.5\text{ V}$, $T_a = 125^\circ\text{C}$			-1.0	mA
Emitter cutoff current	I_{EBO}	$V_{EB} = -5.0\text{ V}$, $I_C = 0$			-3.0	mA
DC current gain	h_{FE1}^*	$V_{CE} = -2.0\text{ V}$, $I_C = -3.0\text{ A}$	2,000		15,000	
DC current gain	h_{FE2}^*	$V_{CE} = -2.0\text{ V}$, $I_C = -5.0\text{ A}$	500			
Collector saturation voltage	$V_{CE(sat)}^*$	$I_C = -3.0\text{ A}$, $I_B = -3.0\text{ mA}$			-1.5	V
Base saturation voltage	$V_{BE(sat)}^*$	$I_C = -3.0\text{ A}$, $I_B = -3.0\text{ mA}$			-2.0	V
Turn-on time	t_{on}	$I_C = -3.0\text{ A}$, $R_L = 17\text{ }\Omega$, $I_{B1} = -I_{B2} = -3.0\text{ mA}$, $V_{CC} \cong -50\text{ V}$ Refer to the test circuit.		0.5		μs
Storage time	t_{stg}			1.0		μs
Fall time	t_f			1.0		μs

* Pulse test $PW \leq 350\text{ }\mu\text{s}$, duty cycle $\leq 2\%$ h_{FE} CLASSIFICATION

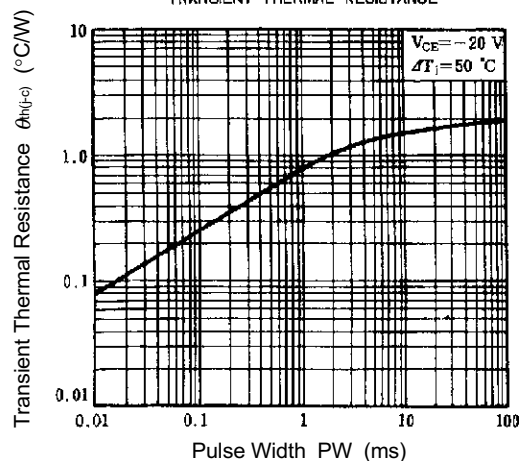
Marking	M	L	K
h_{FE1}	2,000 to 5,000	3,000 to 7,000	5,000 to 15,000

TYPICAL CHARACTERISTICS (Ta = 25°C)

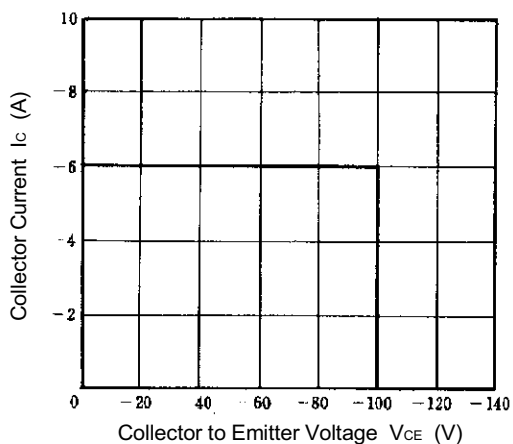
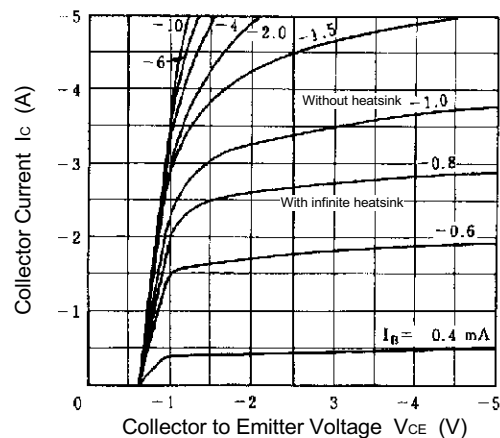


DERATING CURVE OF SAFE
OPERATING AREA

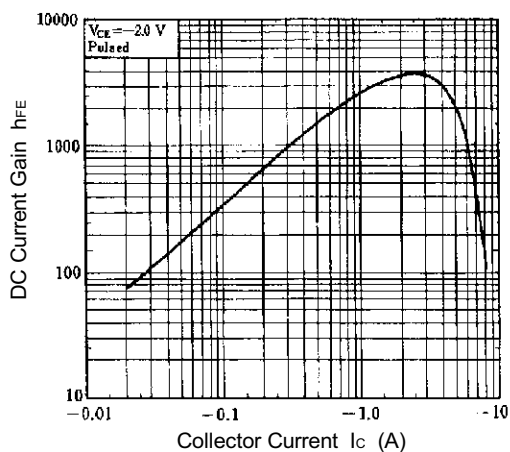
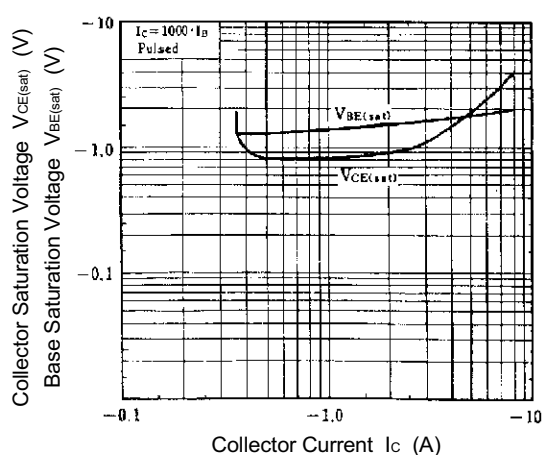
TRANSIENT THERMAL RESISTANCE

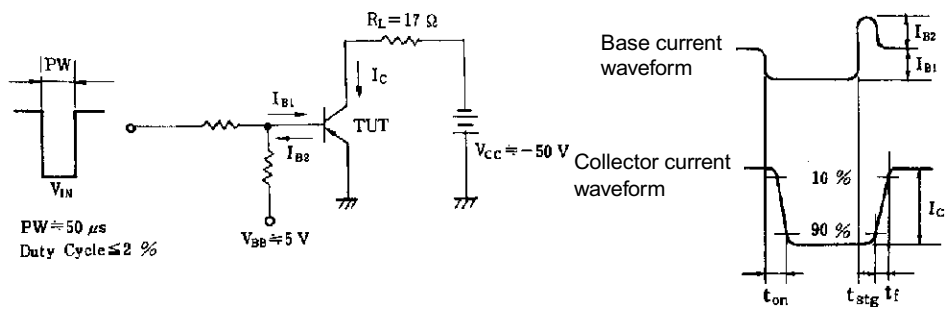


REVERSE BIAS SAFE OPERATING AREAS

COLLECTOR CURRENT vs. COLLECTOR TO
EMITTER VOLTAGE

DC CURRENT GAIN vs. COLLECTOR CURRENT

BASE AND COLLECTOR SATURATION
VOLTAGE vs. COLLECTOR CURRENT

SWITCHING TIME (t_{on} , t_{stg} , t_f) TEST CIRCUIT

[MEMO]

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